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August 29, 2002

Crowell & Moring, LLP P O ox 14300 Washington, DC 20044-4300

granted for the reason specified below. ☐ Refund based upon subsequent establishment of small entity status: A refund based on establishment of small entity status may be granted only if a written assertion of entitlement to small entity status under 37 CFR 1.27 and a request for refund of the excess amount are filed within three months of payment and of the fee (37 CFR 1.28). Three-month period for establishing small entity status and requesting a refund has expired. ☐ Refund of application filing or petition fee: Filing fees paid for an application that is entitled to a filing date and required petition fees are not fees paid by mistake or in excess. If an application is not entitled to a filing date and proceedings are terminated on the application, any filing fees (less the \$130 handling fee) will be refunded (37 CFR 1.53(e)(3)). ☐ Refund of overpayment: There was no overpayment made by applicant. All fees were calculated and assessed properly. \*\*See below\*\* ☐ The payment for which the refund is requested has not been applied to the application. The payment check was returned to applicant for the following reason: ☐ Not filled out properly. (See attached copy of notice.) □ Not made payable in U.S. funds. ☐ No explanation was given as to purpose. ☐ Payment was previously received and applied by Office.

We regret to inform you that your refund request for \$130.00 on application number 09/766835cannot be

\*\*Any request for reconsideration or review of this decision must be by way of a petition filed within two months of this decision, which decision must set forth with particularity why a refund is due (see 37 CFR 1.181(b) and (f)).

☐ Check was returned by bank for insufficient funds.

The sur charge must be paid because the Abstract was missing.

Sincerely,

Eleanor F. Kurtz Office of Initial Patent Examination